Texas Instruments

Reliability Estimator

	Early life failur e rate	MTBF /		Early life failure rate supporting data				MTBF / FIT supporting data						
	ELFR- DPPM		FI T	Con f leve I (%)	Test temp (�C)	Sampl e size	Fail s	Usage	lovo	Activatio n energy (eV)	Test temp (�C)	Test duratio n (hours)	Sampl e size	Fail s
DCR011205 P	TBD	1.29 x 10	7.8	-	-	-	-	55	60.0	0.7	125	1000	1505	0

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